Complete All-Region Model

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Complete All-Region Model

Current Equations (no simplification):

 A key to the generality of the results we are about to develop is the observation that the current in the channel can be caused by both drift and diffusion:

 $I(x) = I_{drift}(x) + I_{diff}(x)$

- The total current in the channel must be the same for all x and equal to the drain-to-source current.
- **Drift current:** Using the shown figure and **previous expressions:**

$$
I_{drift}(x) = \mu(-Q'_I) \frac{W}{\Delta x} (\psi_s(x + \Delta x) - \psi_s(x))
$$

If $\Delta x \rightarrow 0$

$$
I_{drift}(x) = \mu W(-Q'_I) \frac{d\psi_s(x)}{dx}
$$

Diffusion current: using past expressions:

$$
I_{diff}(x) = \mu W \phi_T \frac{dQ'_I}{dx}
$$

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Current Equations

Total current:

$$
I(x) = \mu W(-Q'_I) \frac{d\psi_s(x)}{dx} + \mu W \phi_T \frac{dQ'_I}{dx}
$$

• Parameters at the source end ($x = 0$): ψ_{s0} , Q'_{l0}

Integrating the equation over the L, assuming *I* and μ are constant along the channel:

$$
\int_0^L I_{DS} dx = \int_{\psi_{S0}}^{\psi_{SL}} \mu W(-Q'_I) d\psi_s(x) + \int_{Q'_{I0}}^{Q'_{IL}} \mu W \phi_T dQ'_I
$$

$$
I_{DS} = \frac{W}{L} \mu \left(\int_{\psi_{S0}}^{\psi_{SL}} (-Q'_I) d\psi_s(x) + \int_{Q'_{I0}}^{Q'_{IL}} \phi_T dQ'_I \right)
$$

$$
I_{DS} = I_{DS1} + I_{DS2}
$$

$$
I_{DS1} = \frac{W}{L} \mu \left(\int_{\psi_{S0}}^{\psi_{SL}} (-Q'_I) d\psi_S(x) \right)
$$

$$
I_{DS2} = \frac{W}{L} \mu \left(\int_{Q'_{I0}}^{Q'_{IL}} \phi_T dQ'_I \right)
$$

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Current Equations …

$$
I_{DS2} = \frac{W}{L} \mu \left(\int_{Q'_{I0}}^{Q'_{IL}} \phi_T dQ'_I \right) = \frac{W}{L} \mu \phi_T (Q'_{IL} - Q'_{I0})
$$

 $\mathbb{I}Q'_I$ is a function of ψ_s :

 \blacksquare

$$
Q'_{I} = -C'_{ox}(V_{GB} - V_{FB} - \psi_{S}) - Q'_{B}
$$

\n
$$
I_{DS1} = \frac{W}{L} \mu \left(\int_{\psi_{S0}}^{\psi_{SL}} (-Q'_{I}) d\psi_{S}(x) \right)
$$

\n
$$
= \frac{W}{L} \mu C'_{ox} \left[(V_{GB} - V_{FB})(\psi_{SL} - \psi_{S0}) - \frac{1}{2} (\psi_{SL}^{2} - \psi_{S0}^{2}) \right] + \frac{W}{L} \mu \left(\int_{\psi_{S0}}^{\psi_{SL}} (Q'_{B}) d\psi_{S}(x) \right)
$$

\n
$$
I_{DS2} = \frac{W}{L} \mu C'_{ox} \phi_{T} (\psi_{SL} - \psi_{S0}) - \frac{W}{L} \mu \phi_{T} (Q'_{B} (\psi_{SL}) - Q'_{B} (\psi_{S0}))
$$

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Current Equations …

But we know:

$$
Q'_B = -\sqrt{2q\epsilon_s N_A}\sqrt{\psi_S} = -\gamma C'_{ox}\sqrt{\psi_S}
$$

Substituting to prev. Eq.:

$$
I_{DS1} = \frac{W}{L} \mu C'_{ox} \left[(V_{GB} - V_{FB})(\psi_{SL} - \psi_{S0}) - \frac{1}{2} (\psi_{SL}^2 - \psi_{S0}^2) - \frac{2}{3} \gamma (\psi_{SL}^{3/2} - \psi_{S0}^{3/2}) \right]
$$

$$
I_{DS2} = \frac{W}{L} \mu C'_{ox} \left[\phi_T (\psi_{SL} - \psi_{S0}) - \phi_T \gamma (\psi_{SL}^{1/2} - \psi_{S0}^{1/2}) \right]
$$

Now we have the current in term of surface potential $\psi_{\mathcal{S}}$, therefore if we can evaluate it we can find current.

By substituting V_{CB} to V_{SB} and V_{DB} for each end of channel we have:

$$
\psi_{S0} = V_{GB} - V_{FB} - \gamma \sqrt{\psi_{S0} + e^{-(2\phi_F + V_{SB})/\phi_T} (\phi_T e^{\psi_{S0}/\phi_T})}
$$

$$
\psi_{SL} = V_{GB} - V_{FB} - \gamma \sqrt{\psi_{SL} + e^{-(2\phi_F + V_{DB})/\phi_T} (\phi_T e^{\psi_{SL}/\phi_T})}
$$

These equations can be solved for ψ_{S0} and ψ_{SL} by iteration. This can easily be done with a computer.

- **-Two techniques have emerged as the preferred approaches to compute** $\psi_{\mathcal{S}}$ **.**
	- **First- or second-order Newton-Raphson scheme : uses an iterative numerical procedure, in which a good** initial estimate is made of $\psi_{\mathcal{S}}$. Convergence to tight tolerances can be achieved in two to three iterations.

A plot of ψ_{SL}/ψ_{S0} vs. V_{DB}/V_{SB} is shown ψ_{sL} (ψ_{s0}) The plot saturates at a value dependent on V_{GB} , shown in Fig. Edge effect near drain and source are neglected here. (small dimension effect) . $\psi_{sa}(V_{GB})$ Now to plot \underline{fig} . we raise the V_{DB} voltage (as a parameter) respect to $\boldsymbol{V_{SB}}$ (keep it fix). ψ_{SL} and ψ_{SO} can be calculated from previous equations respect to V_{DB} and V_{SB} . Now with [current equations](#page-4-0) we can find I_{DS1} and $2\phi_F$ I_{DS2} . Finally $I_{DS} = I_{DS1} + I_{DS2}$ **Note:** described equations predicts the current in all these regions. Experiments agree well with this expression

- Saturation always take place for large V_{DR} .
- For following figure saturation effect is shown for specific V_{GB} (= V_{GB4}).
- Drain end of the channel:
	- Increasing $\boldsymbol{V_{\text{DB}}}$ eventually drives the drain end of the channel into weak inversion and then depletion, where ψ_{SL} becomes practically constant at a value that depends only on $V_{GB}^{'}(=V_{GB4})$.
	- **Increasing** V_{DB} **further has little effect on** ψ_{SL} **and** $|Q_I|$ **becomes very small· Thus** I_{DS1} and I_{DS2} also become independent of $\boldsymbol{V_{DB}}.$

Source end of the channel:

- As the V_{SB} is constant and it selected so that the this part be at strong inversion therefore it is heavily inverted due to very large $|Q_I'|$.
- $\mathbf{\psi}_{\text{S}}$ is strongly dependent to \mathbf{V}_{S} .
- **The current at any point in the channel should be constant and it is not** dependent only to $|Q'_I|$ as shown in [previous equations.](#page-2-0) (drift and diffusion)

- In this figure consider that \boldsymbol{V}_{DB} selected so that \boldsymbol{I}_{DS} is in saturation region.
- By changing the V_{GB} , I_{DS} components I_{DS1} and I_{DS2} can be calculated.
- To include a large range of currents, a logarithmic vertical axis is used.
- Here $V_{DB} > V_{SB}$, so that the more heavily inverted channel end is the one next to the source.
- Everything below moderate inversion is called weak inversion.
- \blacksquare It is seen in Fig. that:
	- In **strong** inversion, $I_{DS} \approx I_{DS1}$, so the current is mainly due to the presence of drift.
	- In *weak* inversion, $I_{DS} \approx I_{DS2}$, so the current is mainly due to the presence of diffusion.
	- In *moderate* inversion *both I_{DS1}* and *I_{DS2}* are important.

- In following Fig., we show a comparison of the preceding model (lines) to full computer solution of the semiconductor equations (dots)·
- The simulation is a 2D numerical solution of the Poisson and drift-diffusion equations, allowing for the spreading of the inversion layer below the surface. The values of W and *L* used were on purpose chosen very large, to minimize edge effects.

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A Graphical Interpretation

■ In this figure, we show $-Q'_I$ vs. ψ_S , as obtained from below Eq., for a given V_{GB} .

$$
Q'_I = -C'_{ox}(V_{GB} - V_{FB} - \psi_s - \gamma \sqrt{\psi_s})
$$

- The only part of this curve that is relevant to us is that between ψ_{so} and ψ_{SL} the values of the surface potential at the source and the drain.
- This curve should also satisfy following Eq. (derived for 3 terminal device C_{ox} $(V_{GB} V_{FB})$ before) :

$$
Q'_{I} = -\sqrt{2q\epsilon_{s}N_{A}}\left(\sqrt{\psi_{s} + \phi_{T}e^{(\psi_{s}-(2\phi_{F}+\mathbf{V}_{CB}))/\phi_{T}}}-\sqrt{\psi_{s}}\right)
$$

- \mathbf{Q}_{I0}' and Q_{IL}' corresponds to surface potential ψ_{S0} and ψ_{SL} .
- **Shaded region is regarding to following integral:**

$$
\boldsymbol{I_{DS1}} = \frac{W}{L} \mu \left(\int_{\psi_{S0}}^{\psi_{SL}} (-Q'_I) d\psi_S(x) \right)
$$

let us determine the point where the curve representing above Eq intersects the horizontal axis.

This can be found by setting that equation equal to zero and solving for ψ_s **.** The result is nothing but ψ_{Sa} . (first introduced in 2 terminal device)

 ψ_{Sq} is the potential which inversion layer is negligible.

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A Graphical Interpretation…

- The graphical construction in previous Fig. facilitates a feel for the behavior of I_{DS1} and I_{DS2} .
- The particular operating point assumed in previous Fig. happens to be in the strong inversion nonsaturation region. Why ?
	- When V_{DB} is raised a little, the corresponding $-Q'_l$; curve will move to the right in the figure; the value of ψ_{SL} will increase, and so will the currents in [Eq.](#page-4-0) thus $I_{DS} = I_{DS1} + I_{DS2}$ is increase.
- **E**ventually, as V_{DB} is raised further, the corresponding Q'_i ; plot will move far to the right, as illustrated by the broken-line curve; ψ_{SL} will asymptotically reach the value ψ_{Sa} and will be unable to rise further.
- \mathbf{Q}_{IL}' now becomes essentially zero, and the trapezoid becomes a triangle; $\mathbf{I_{DS1}}$ and $\mathbf{I_{DS2}}$ stay fixed as $\boldsymbol{V}_{\boldsymbol{D}\boldsymbol{B}}$ is raised further.
- We have now reached *saturation*, and the current flattens out at its maximum value.

Symmetry

It is clear from [previous Eqs.](#page-4-0) that I_{DS} can be written in the form:

$$
I_{DS} = \frac{W}{L}(f(\psi_{SL}) - f(\psi_{S0}))
$$

$$
f(\psi_S) = \mu C'_{ox} \left[(V_{GB} - V_{FB} + \phi_T)\psi_S + \phi_T \gamma \psi_S^{1/2} - \frac{1}{2}\psi_S^2 - \frac{2}{3}\gamma \psi_S^{3/2} \right]
$$

This Eqs. is in a form that emphasizes the symmetry of the transistor.

If the potentials at the source and drain are interchanged, the only difference will be that I_{DS} will change sign.

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Surface Potential, Charge, and Currents vs. Position

For visualizing transistor operation and for calculating certain quantities, it will be useful to relate the surface potential $\psi_{\mathcal{S}}$ to the position along the channel $x.$

$$
I_{DS} = \frac{W}{L} F(\psi_{SL}, \psi_{S0})
$$

where *F* is an appropriate function.

Furthermore as the current is independent of x **therefore:**

$$
I_{DS} = \frac{W}{x} F(\psi_S(x), \psi_{S0})
$$

Eliminating I_{DS} between the preceding two equations we obtain:

$$
\frac{x}{L} = \frac{F(\psi_S(x), \psi_{S0})}{F(\psi_{SL}, \psi_{S0})}
$$

This equation gives the relation between x and $\psi_{S}(x)$.

Surface Potential, Charge, …

The easy way to get results from it is to give values $\psi_{S}(x)$ between ψ_{S0} and ψ_{SL} and determine *x*. The results is shown in following *figure.*

Regions of inversions:

- In **moderate inversion**, the variation of ψ_s with x for $V_{DR} > V_{SR}$ is less pronounced.
- **If all as inversion**, the two curves would practically coincide because, in that region, the variations of the surface potential along the channel is negligible even when $V_{\text{DR}} > V_{\text{SR}}$.

 $\lceil Q_I' \rceil$ as [predicted](#page-10-0) by the all-region model decreases monotonically along the channel as we go from the source toward the drain, although we can see it here as well. As the potential increase…

One can similarly evaluate $\frac{d\psi_s(x)}{dx}$ and $\frac{dQ'_I}{dx}$ $\frac{dQ_I}{dx}$ as a function of x.

It is then found that $I_{drift}(x)$ decreases with *x*, whereas $I_{diff}(x)$ increases.

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 $\psi_{\rm s}(x)$